

Test Report

No.SZR150714004001

Date: Jul. 15, 2015

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Applicant : Shanghai High-Flying Electronics Technology Co., Ltd
Address : Room 1002,Building 1,No.3000,Longdong Avenue,Pudong New Area,Shanghai,China,201203

The submitted sample and sample information was/were submitted and identified by/on the behalf of the client

Sample name : Wi-Fi Module
Type /model : HF-A21-SMT
Manufacturer : /
Sample received date : Jul. 14, 2015
Testing period : Jul. 14, 2015 to Jul. 15, 2015

Test requested : 1. As specified by client, to screen Lead(Pb), Cadmium(Cd), Mercury(Hg), Chromium(Cr) and Bromine(Br) in the submitted sample(s) by XRF.
2. As specified by client, when screening results exceed the XRF screening limit in IEC 62321-3-1:2013, further use of chemical methods are required to test the Lead(Pb), Cadmium(Cd), Mercury(Hg), Hexavalent Chromium(Cr(VI)), Polybrominated Biphenyls(PBBs), Polybrominated Diphenyl Ethers(PBDEs) in the submitted samples.

According to the RoHS Directive 2011/65/EU

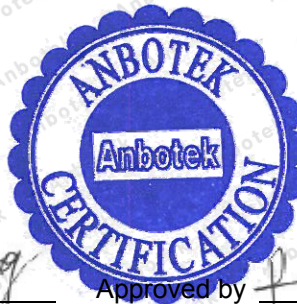
Test Method: Please refer to the following page(s).

Test Result(s): Please refer to the following page(s).

Tested by Saihen Chen

Inspected by Linshang

Approved by Hosang Luo



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Test Method:
A. Screening test by XRF spectroscopy

XRF screening limits in mg/kg for regulated elements according to IEC 62321-3-1:2013.

Element	Limit of IEC 62321-3-1:2013. Unit (mg/kg)		MDL	
	Polymers and metals	Composite material	Polymers	Other material
Pb	$BL \leq (700-3\sigma) < X < (1300+3\sigma)$ $\leq OL$	$BL \leq (500-3\sigma) < X < (1500+3\sigma)$ $\leq OL$	10 mg/kg	50 mg/kg
Cd	$BL \leq (70-3\sigma) < X < (130+3\sigma)$ $\leq OL$	$LOD \leq (50-3\sigma) < X < (150+3\sigma)$ $\leq OL$	10 mg/kg	50 mg/kg
Hg	$BL \leq (700-3\sigma) < X < (1300+3\sigma)$ $\leq OL$	$BL \leq (500-3\sigma) < X < (1500+3\sigma)$ $\leq OL$	10 mg/kg	50 mg/kg
Cr	$BL \leq (700-3\sigma) < X$	$BL \leq (500-3\sigma) < X$	10 mg/kg	50 mg/kg
Br	$BL \leq (300-3\sigma) < X$	$BL \leq (250-3\sigma) < X$	10 mg/kg	50 mg/kg

Note:

-BL = Under the XRF screening limit

-OL = Further chemical test will be conducted while result is above the screening limit

-X= The symbol "X" marks the region where further investigation is necessary

-3 σ = The reproducibility of analytical instruments

-LOD= Detection limit

B. Chemical Test

Test Item(s)	Test Method	Measured Equipment(s)	MDL
Lead (Pb)/ Cadmium (Cd)	IEC 62321-5:2013 Ed.1.0	ICP-OES	2 mg/kg
Mercury (Hg)	IEC 62321-4:2013 Ed.1.0	ICP-OES	2 mg/kg
Hexavalent Chromium Cr(VI)	IEC 62321:2008 Ed.1 Annex B	UV-VIS	/
	IEC 62321:2008 Ed.1 Annex C	UV-VIS	2 mg/kg
Polybrominated Biphenyls (PBBs)	IEC 62321:2008 Ed.1 Annex A	GC-MS	5 mg/kg
Polybrominated Diphenyl Ethers (PBDEs)	IEC 62321:2008 Ed.1 Annex A	GC-MS	5 mg/kg

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Test Results:

Sample No.	Sample Description	Tested Items	XRF Screening Test Unit (mg/kg)	Chemical Test Unit (mg/kg)	Conclusion
1	Silvery metal shell	Pb	BL	/	PASS
		Cd	BL	/	
		Hg	BL	/	
		Cr(Cr(VI))	BL	/	
		Br(PBBs&PBDEs)	/	/	
2	Green PCB board	Pb	BL	/	PASS
		Cd	LOD	/	
		Hg	BL	/	
		Cr(Cr(VI))	BL	/	
		Br(PBBs&PBDEs)	X	N.D.	
3	Black IC	Pb	BL	/	PASS
		Cd	LOD	/	
		Hg	BL	/	
		Cr(Cr(VI))	BL	/	
		Br(PBBs&PBDEs)	BL	/	
4	Black IC	Pb	BL	/	PASS
		Cd	LOD	/	
		Hg	BL	/	
		Cr(Cr(VI))	BL	/	
		Br(PBBs&PBDEs)	BL	/	
5	Crystal oscillator	Pb	BL	/	PASS
		Cd	LOD	/	
		Hg	BL	/	
		Cr(Cr(VI))	BL	/	
		Br(PBBs&PBDEs)	/	/	
6	Chip coil industrial	Pb	BL	/	PASS
		Cd	LOD	/	
		Hg	BL	/	
		Cr(Cr(VI))	BL	/	
		Br(PBBs&PBDEs)	BL	/	

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Sample No.	Sample Description	Tested Items	XRF Screening Test Unit (mg/kg)	Chemical Test Unit (mg/kg)	Conclusion
7	Brown chip capacitor	Pb	BL	/	PASS
		Cd	LOD	/	
		Hg	BL	/	
		Cr(Cr(VI))	BL	/	
		Br(PBBs&PBDEs)	BL	/	
8	Black chip capacitor	Pb	BL	/	PASS
		Cd	LOD	/	
		Hg	BL	/	
		Cr(Cr(VI))	BL	/	
		Br(PBBs&PBDEs)	BL	/	
9	White chip capacitor	Pb	BL	/	PASS
		Cd	LOD	/	
		Hg	BL	/	
		Cr(Cr(VI))	BL	/	
		Br(PBBs&PBDEs)	BL	/	

Note:

-MDL = Method Detection Limit

-N.D. = Not Detected (<MDL)

-mg/kg = ppm = parts per million

 -Negative = Absence of Cr(VI) , the detected Cr(VI) concentration in the boiling water extraction solution is less than 0.02 mg/kg with 50cm² sample surface area used.

 -Positive = Presence of Cr(VI), the detected Cr(VI) concentration in the boiling water extraction solution is equal to or greater than 0.02 mg/kg with 50cm² sample surface area used.

Remark:

- The screening results are only used for reference.

- When conducting the test for PBBs&PBDEs, XRF was introduced to screen Br Exclusively; When conducting the test for Hexavalent Chromium, XRF was introduced to screen Chromium exclusively.

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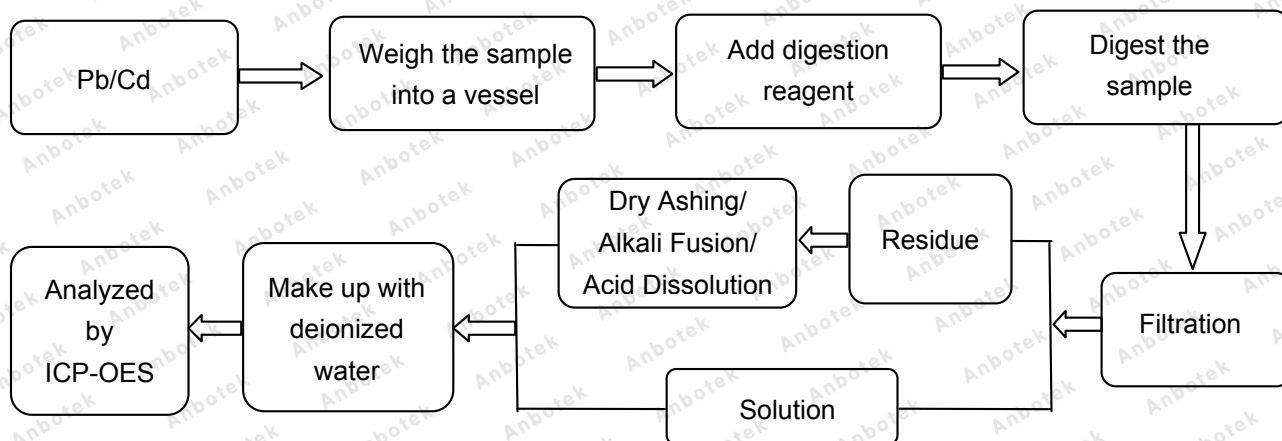
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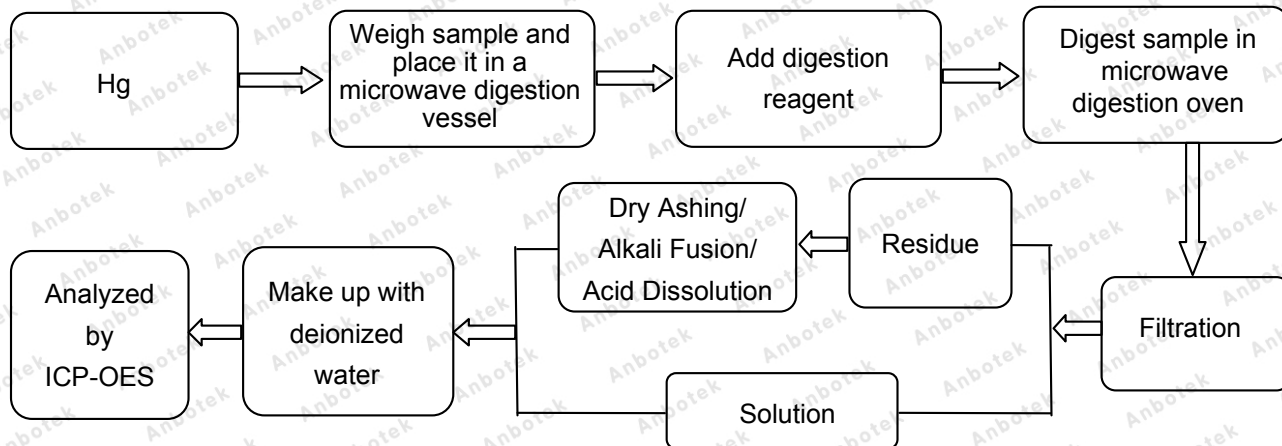
Test Process:

The sample(s) had been dissolved totally tested for Lead, Cadmium, Mercury.

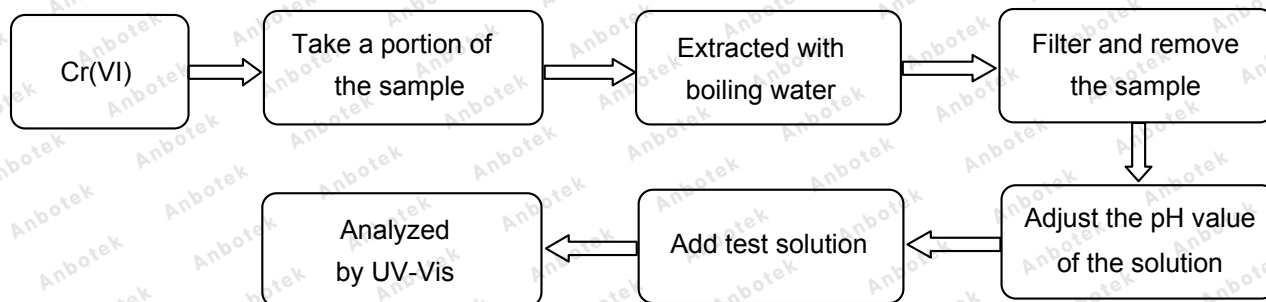
◆ IEC 62321-5:2013 Ed.1.0



◆ IEC 62321-4:2013 Ed.1.0



◆ IEC 62321:2008 Ed.1 Annex B



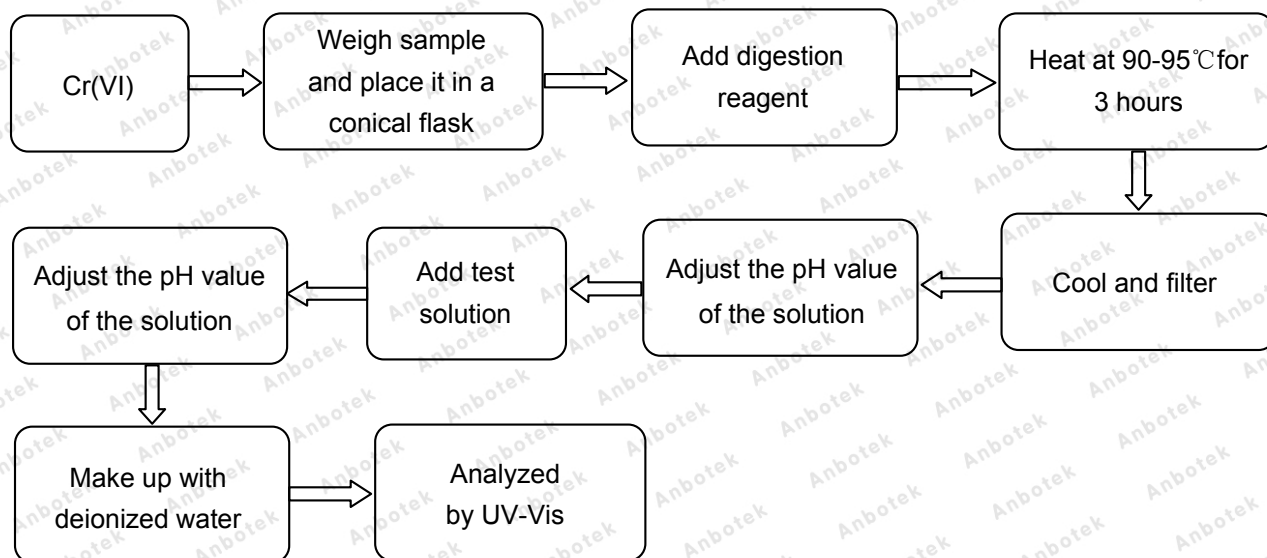
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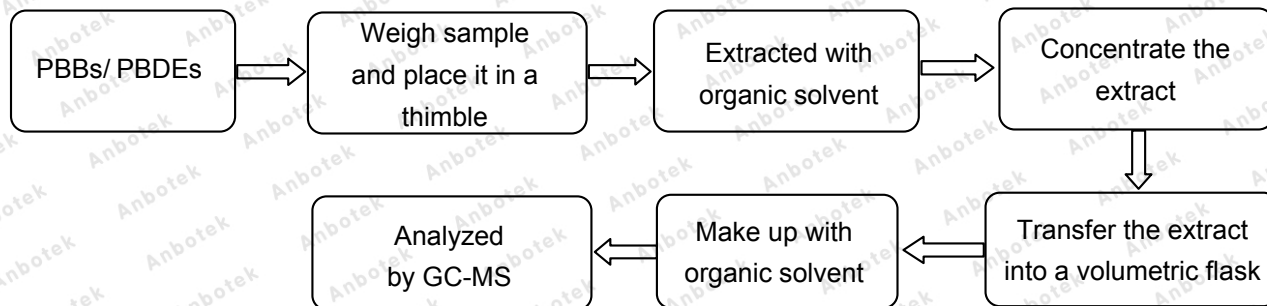
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◆ IEC 62321:2008 Ed.1 Annex C



◆ IEC 62321:2008 Ed.1 Annex A



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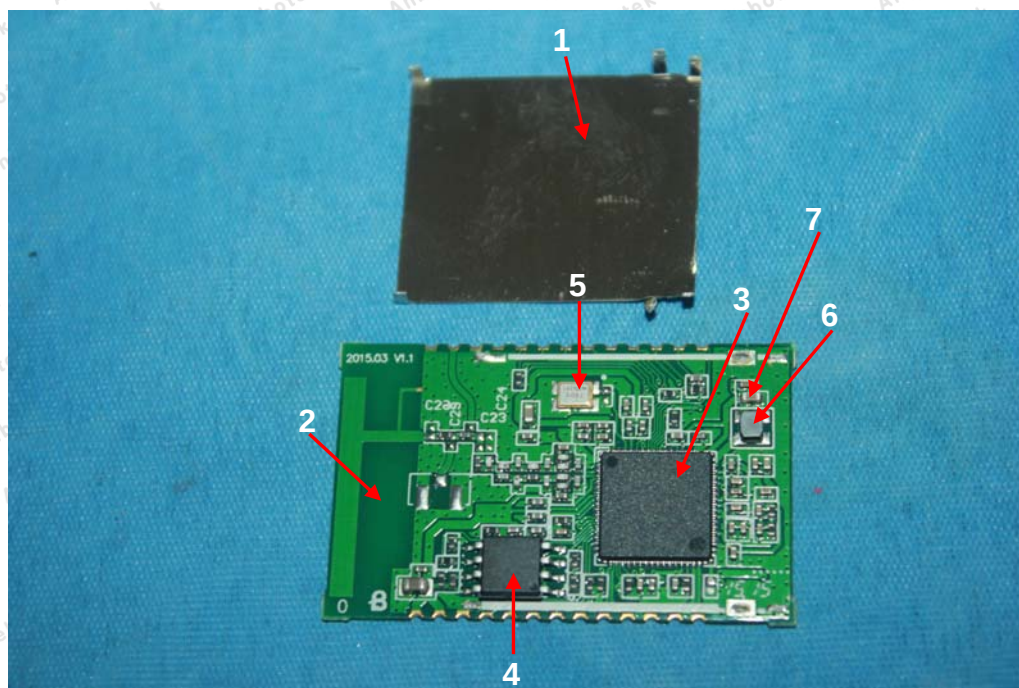
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Photograph of Sample



Photo(s) of the tested component(s)



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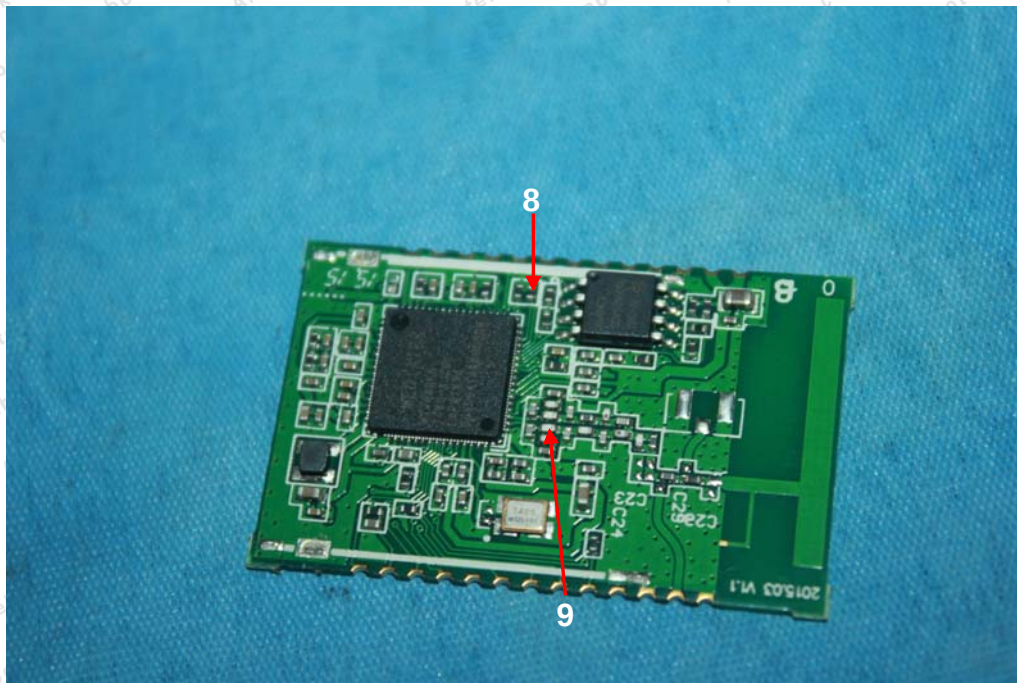
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***** End of Report *****

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